



US0D1006252S

(12)

United States Design Patent

Fukushi et al.

(10)

Patent No.:

US D1,006,252 S

(45)

Date of Patent:

** Nov. 28, 2023

(54) SAMPLE RACK

FOREIGN PATENT DOCUMENTS

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CN 307988933 * 4/2023

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U.S. Appl. No. 29/828,132, filed Feb. 24, 2022.

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Tokyo (JP)

Primary Examiner — Omeed Agilee

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(**) Term: 15 Years

(57) CLAIM

The ornamental design for a sample rack, as shown and described.

(21) Appl. No.: 29/828,131

(22) Filed: Feb. 24, 2022

DESCRIPTION

(30) Foreign Application Priority Data

Aug. 27, 2021 (JP) 2021-018555 D

(51) LOC (14) Cl. 24-02

(52) U.S. Cl.
USPC D24/229

(58) Field of Classification Search

USPC D24/107, 108, 127, 128, 216, 217, 219,
D24/224, 226–232; D10/81

CPC B01L 9/06; B01L 9/65; B01L 9/00; B01L
3/5025; B01L 3/508; B01L 3/5082; A61J
1/00; A61J 1/12; A61J 1/065; A61J
1/067; G01N 35/026; G01N 35/02

See application file for complete search history.

FIG. 1 is a front, top and right side perspective view of a sample rack according to the design;

FIG. 2 is a rear, top and left side perspective view thereof.

FIG. 3 is a rear, bottom and left side perspective view thereof;

FIG. 4 is a front elevational view thereof;

FIG. 5 is a rear elevational view thereof;

FIG. 6 is a left side elevational view thereof;

FIG. 7 is a right side elevational view thereof;

FIG. 8 is a top plan view thereof;

FIG. 9 is a bottom plan view thereof;

FIG. 10 is a cross-sectional view taken along line 10-10 of FIG. 4;

FIG. 11 is a cross-sectional view taken along line 11-11 of FIG. 8;

FIG. 12 is a cross-sectional view taken along line 12-12 of FIG. 8;

FIG. 13 is a cross-sectional view taken along line 13-13 of FIG. 4; and,

FIG. 14 is a cross-sectional view taken along line 14-14 of FIG. 4.

The broken lines illustrate portions of the sample rack that form no part of the claimed design.

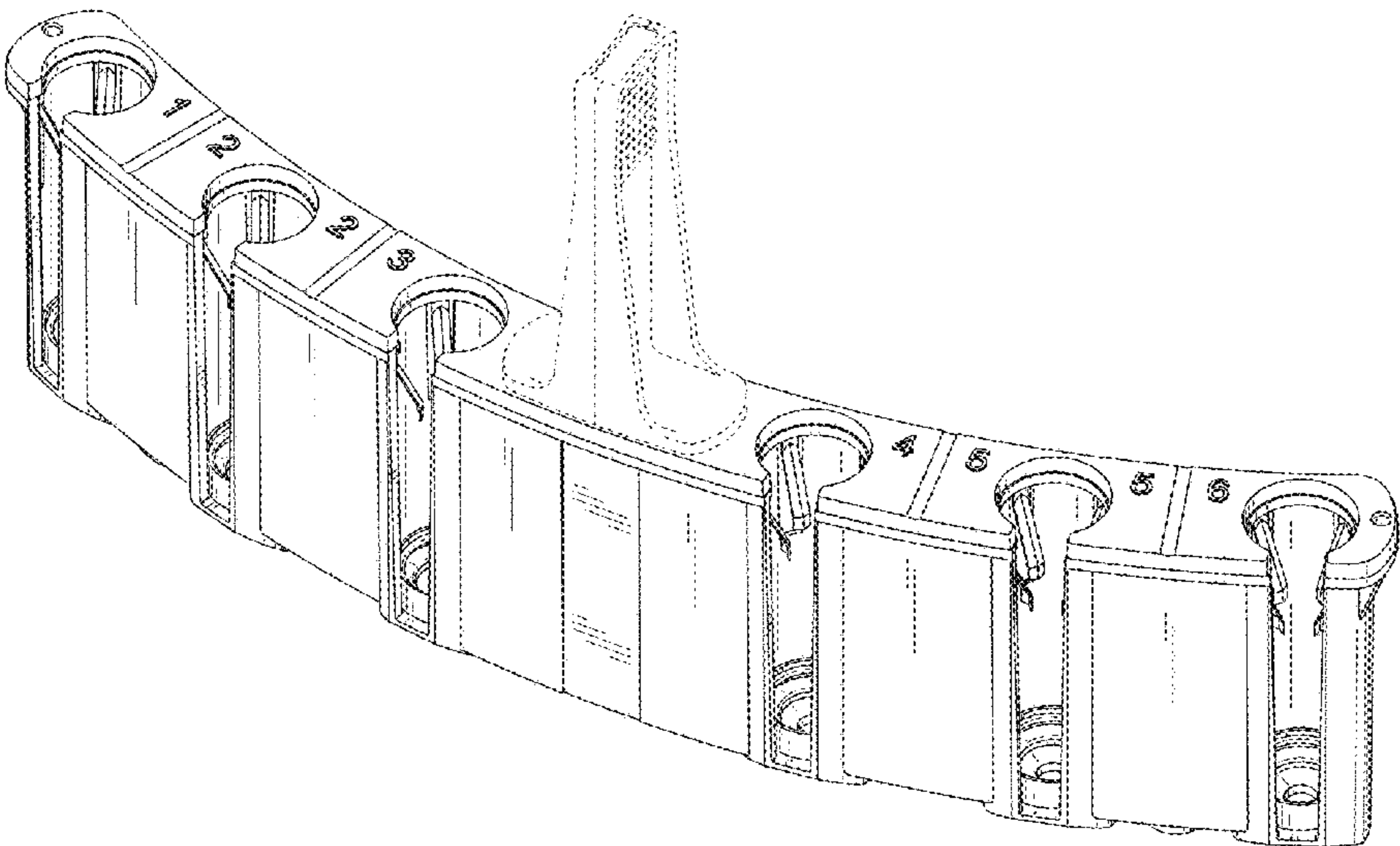
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1 Claim, 10 Drawing Sheets



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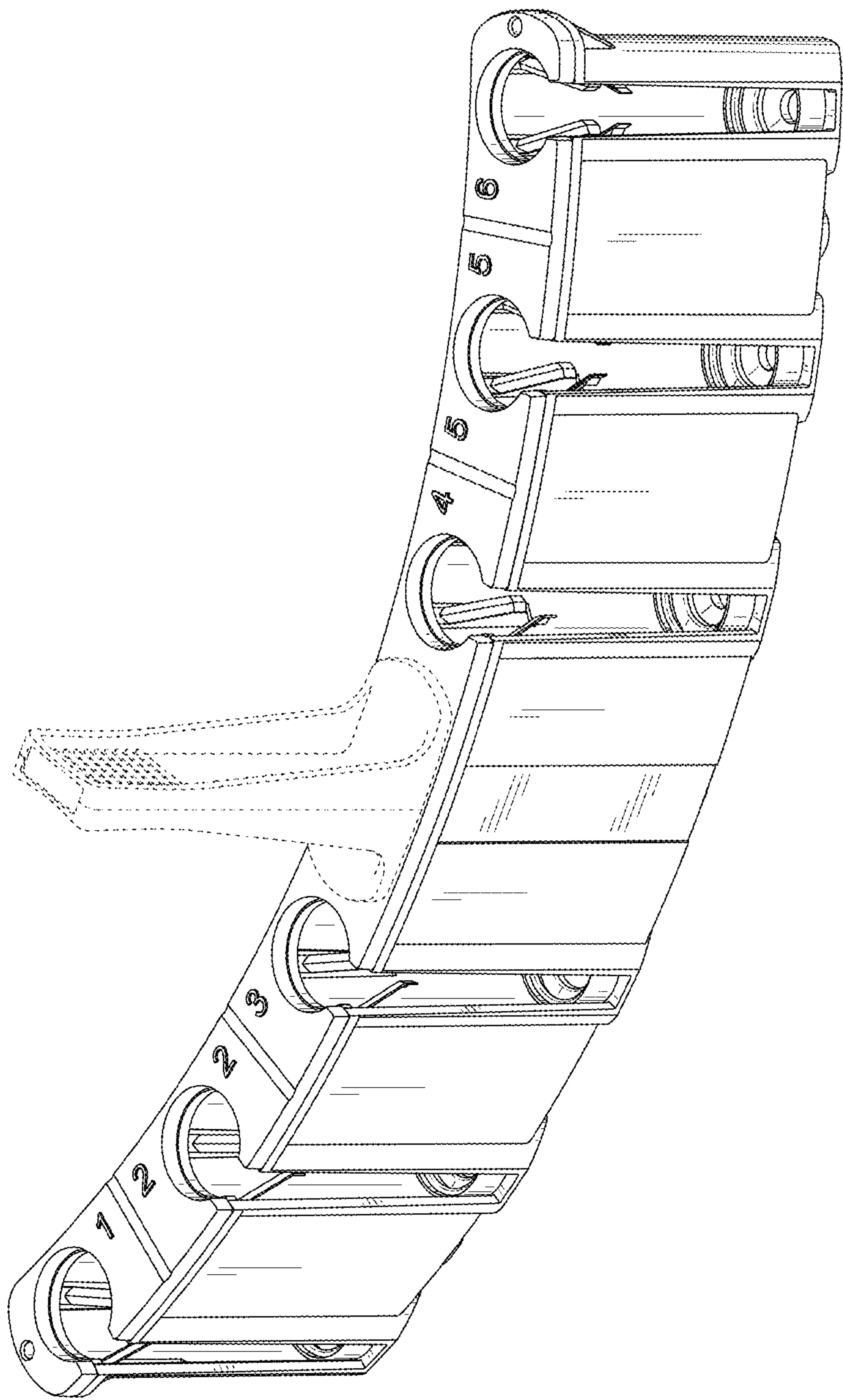


FIG. 1

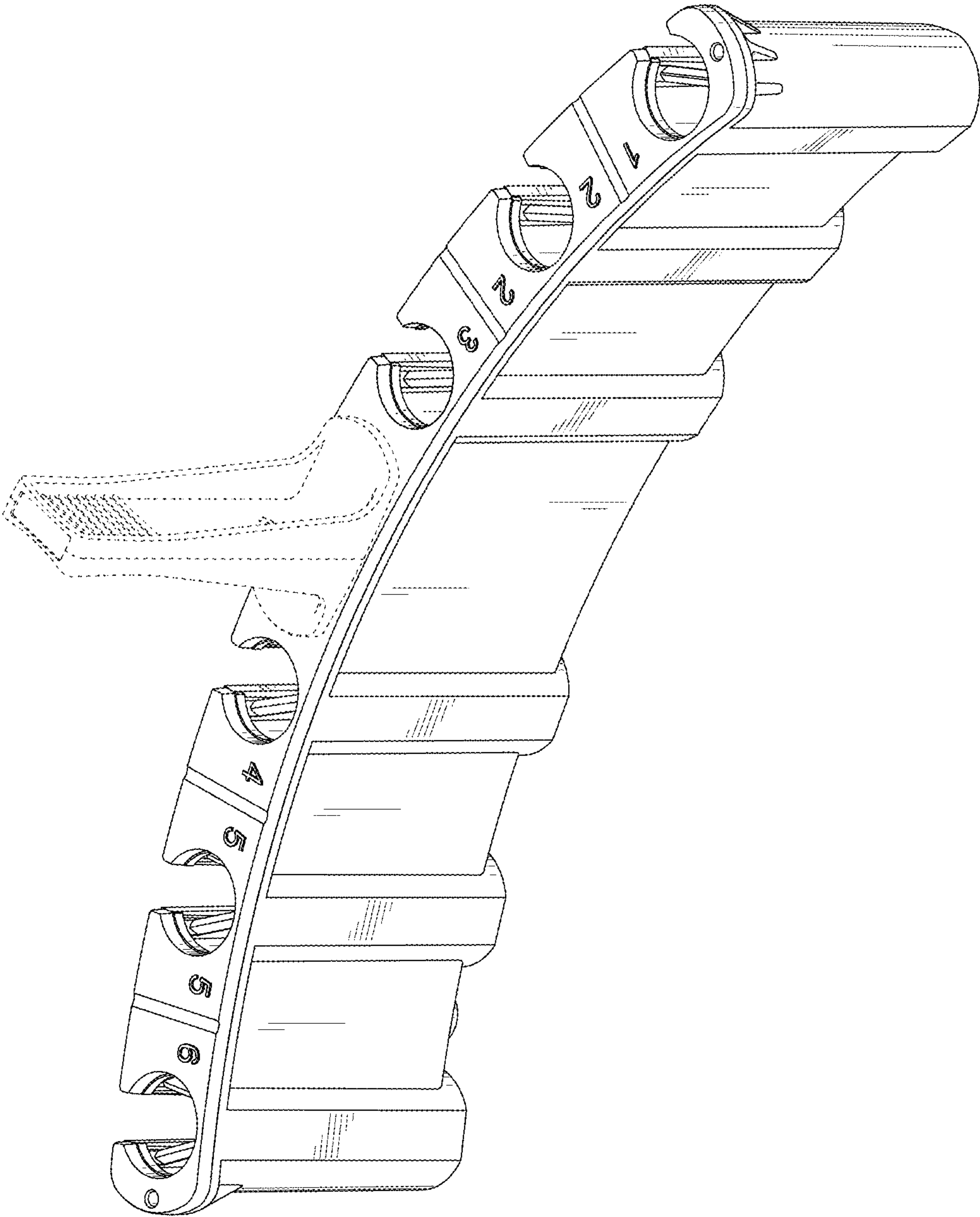


FIG. 2

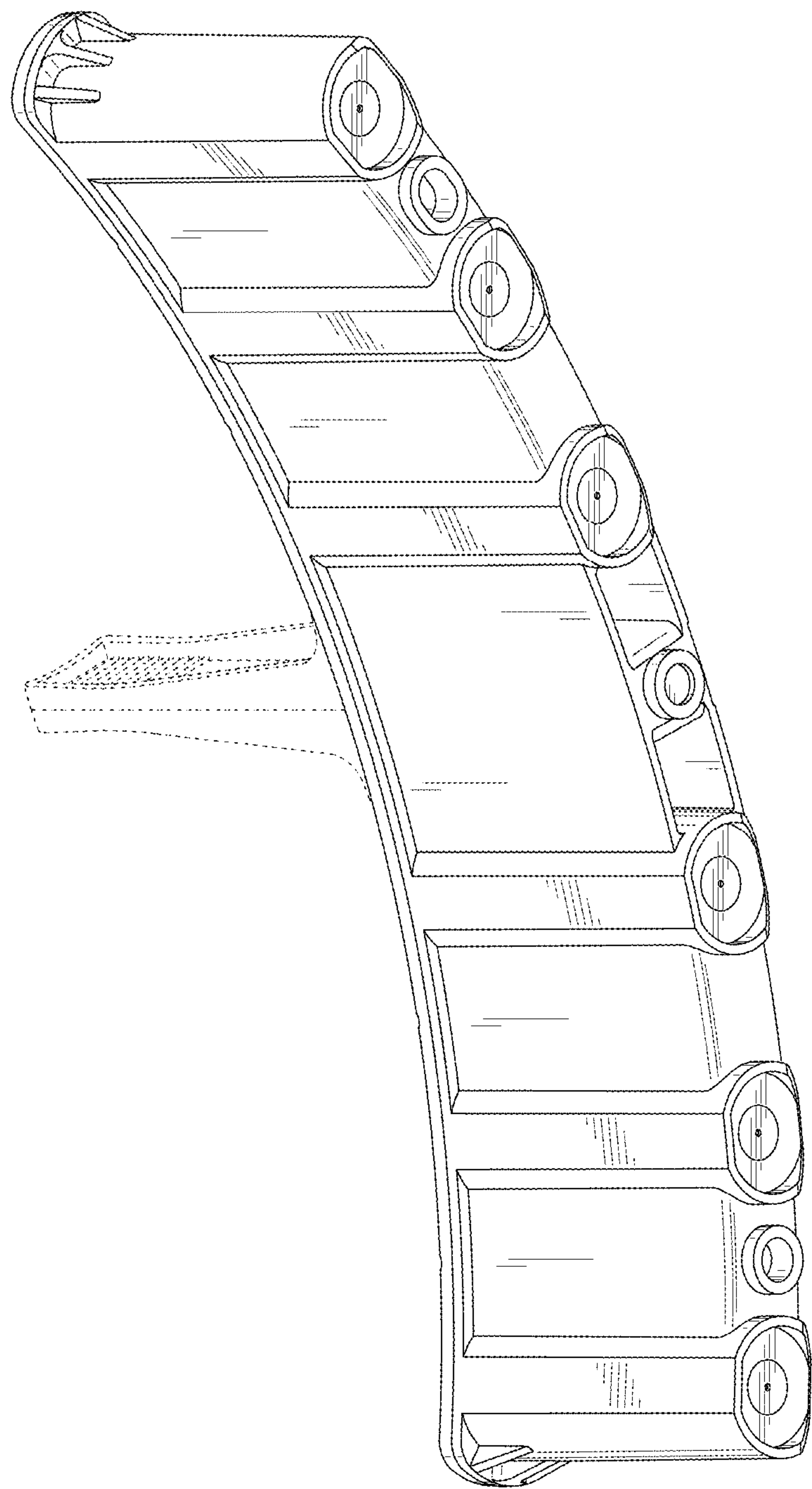


FIG. 3

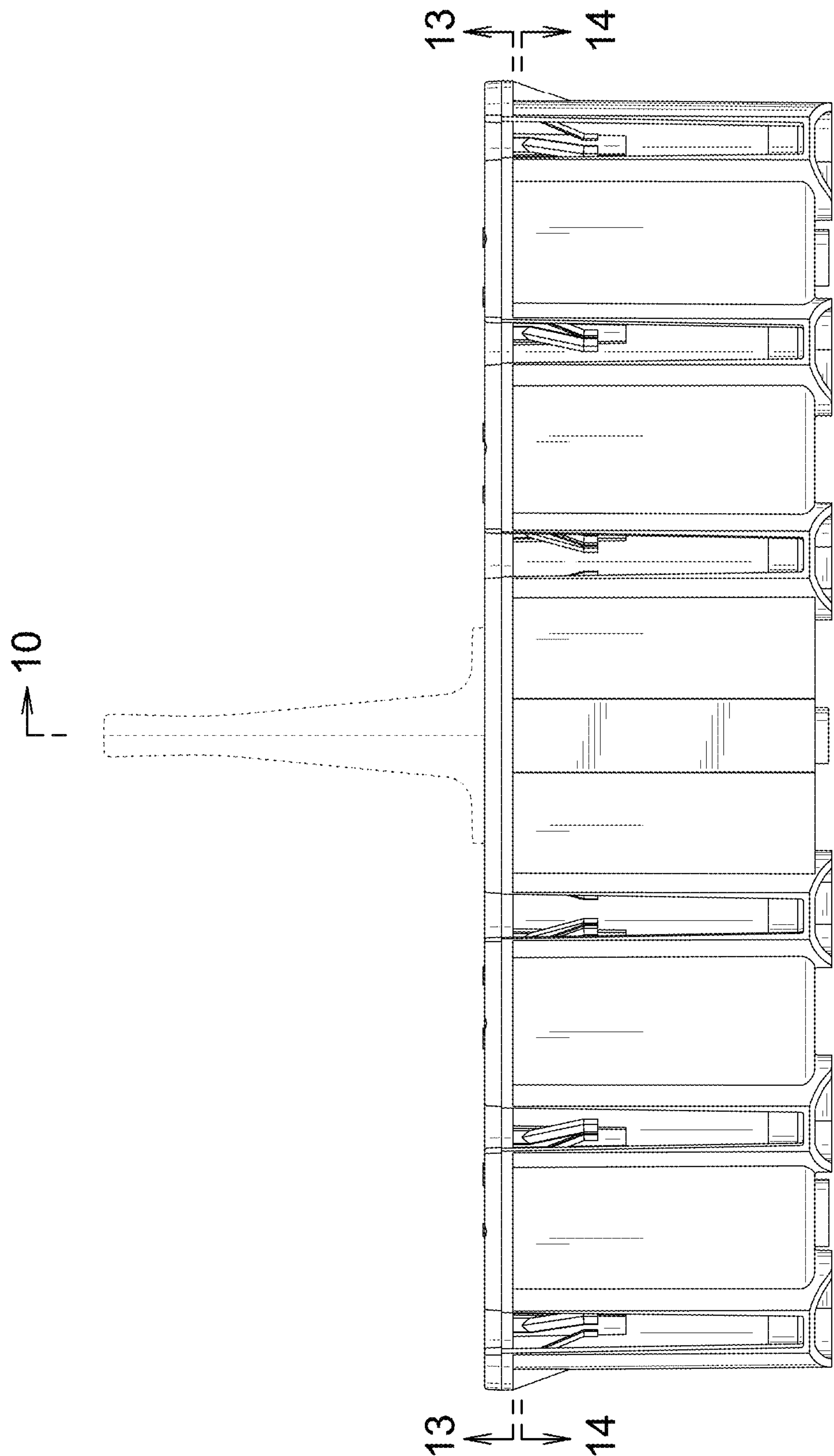


FIG. 4

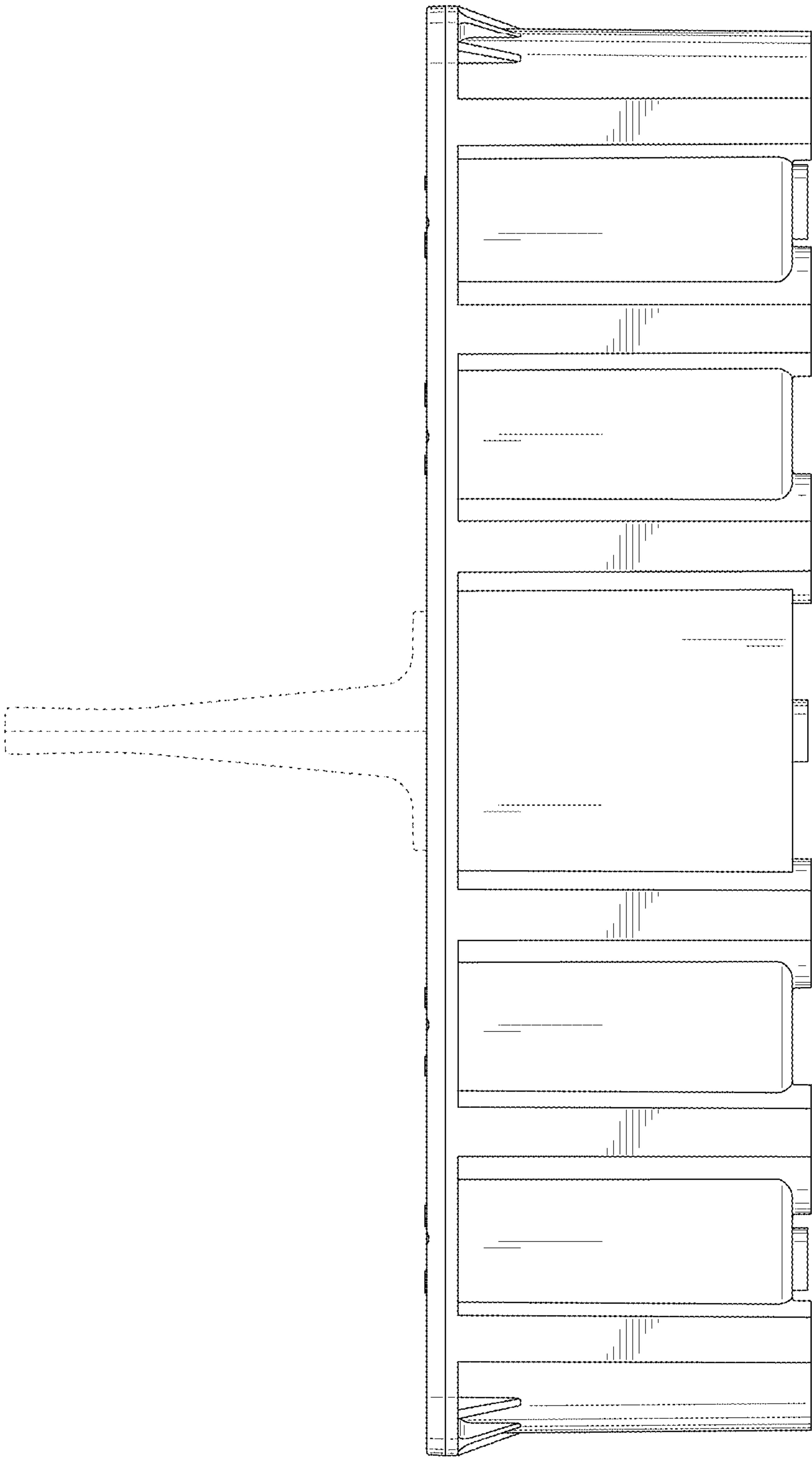


FIG. 5

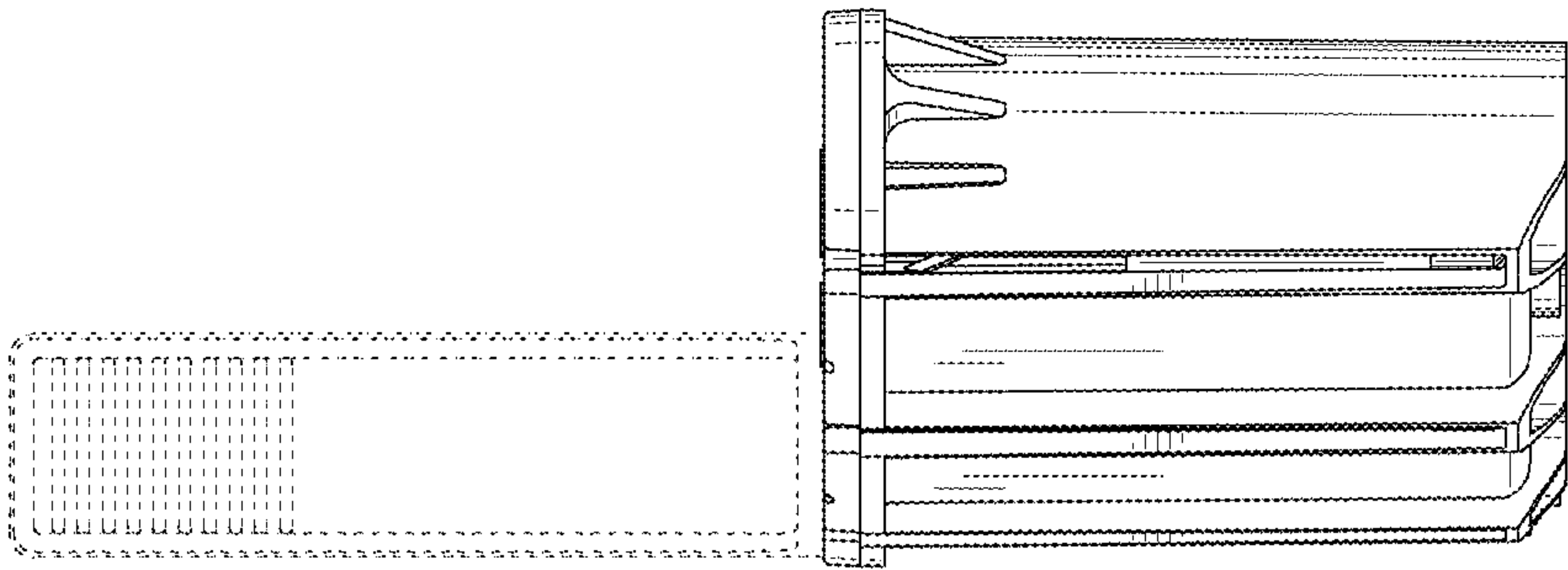


FIG. 7

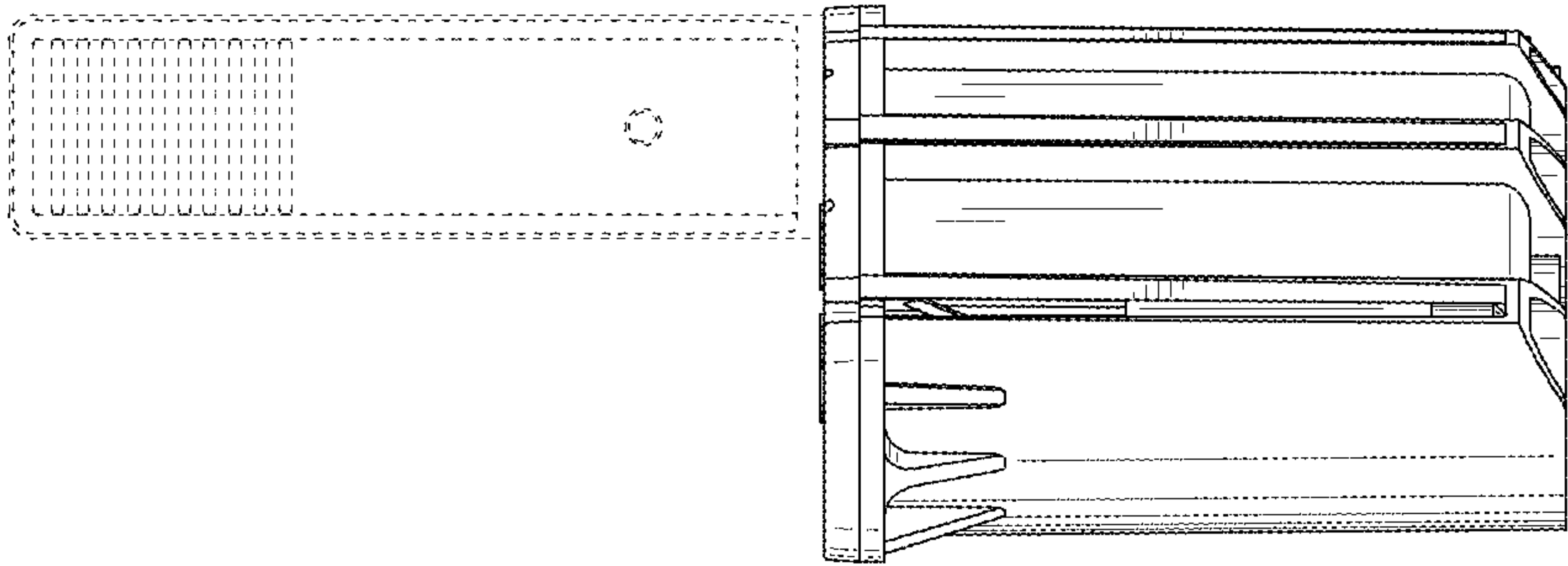


FIG. 6

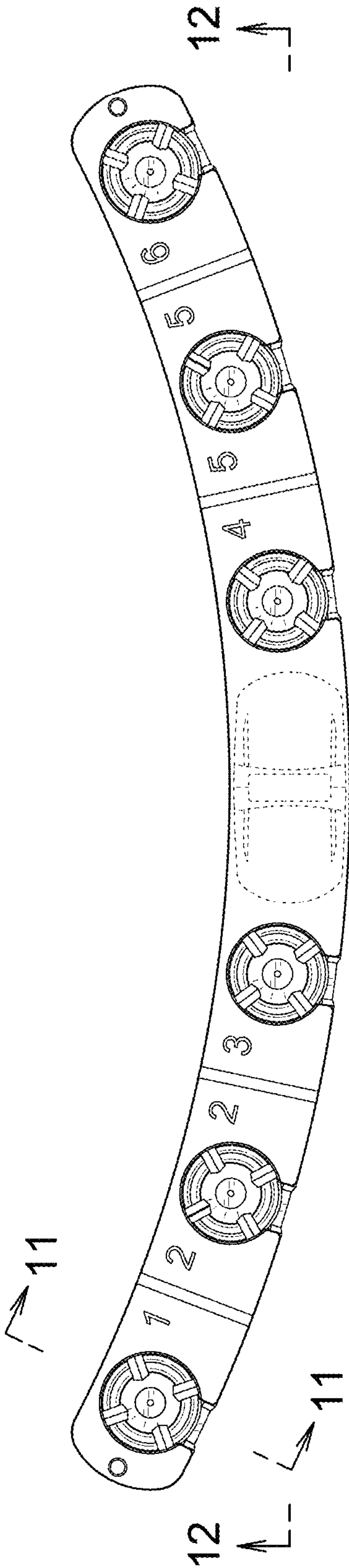


FIG. 8

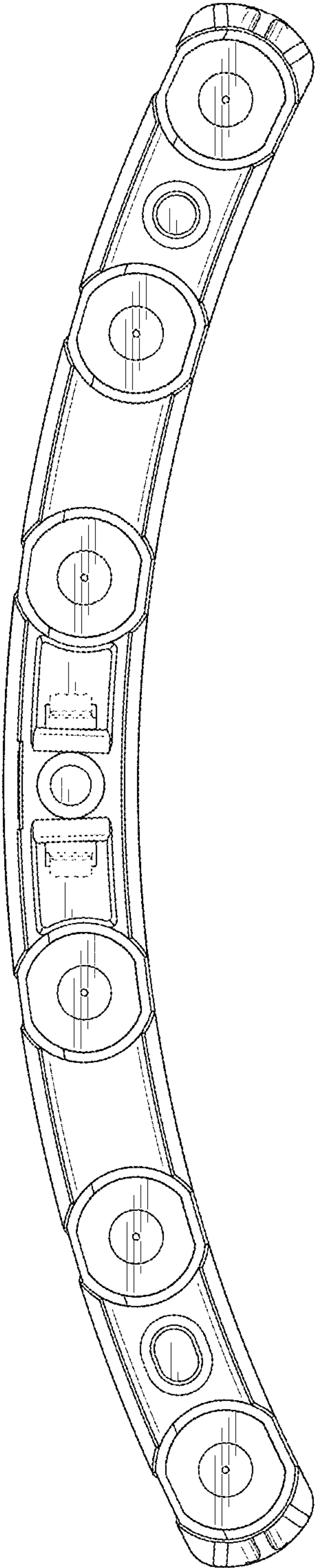


FIG. 9

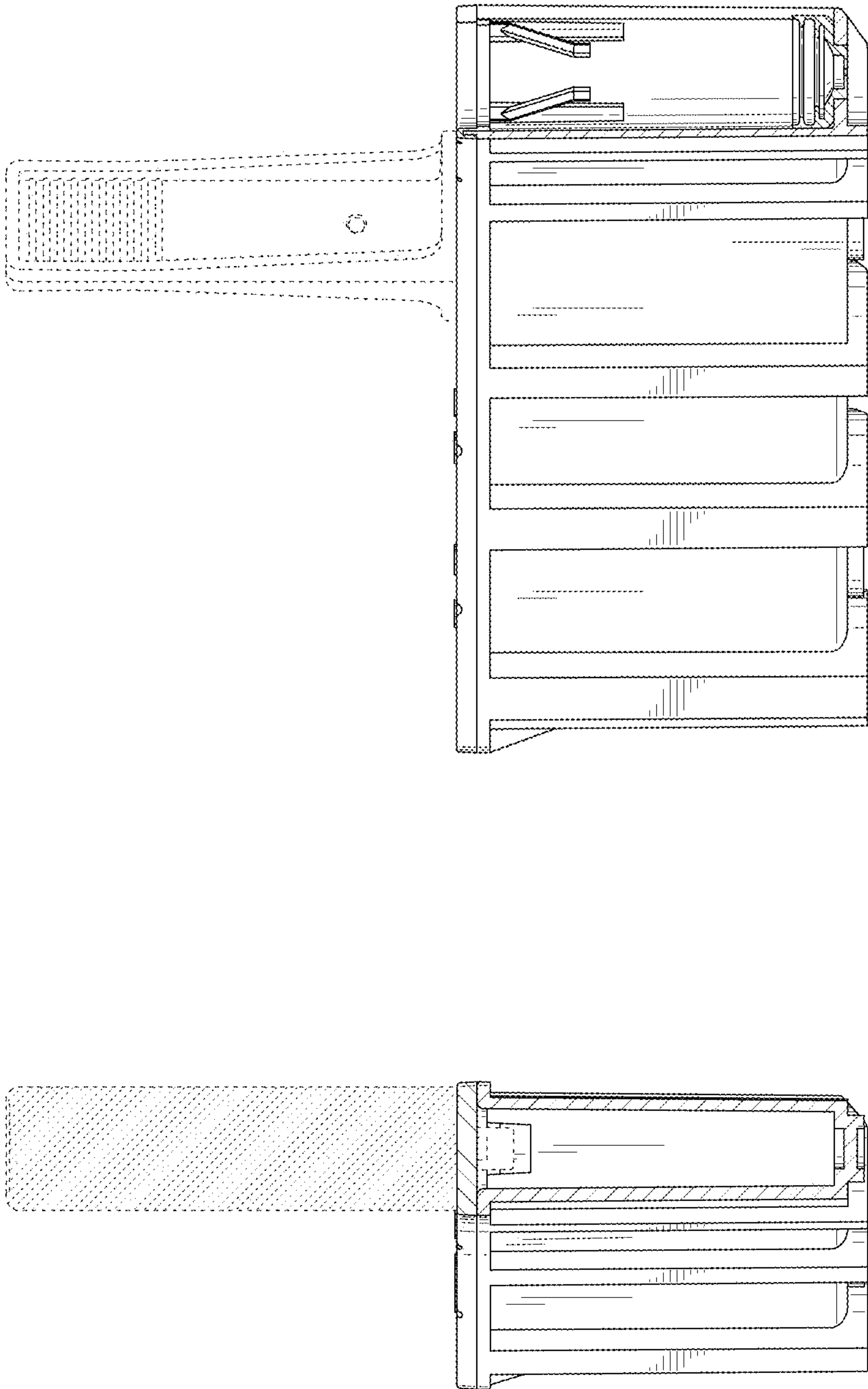


FIG. 10

FIG. 11

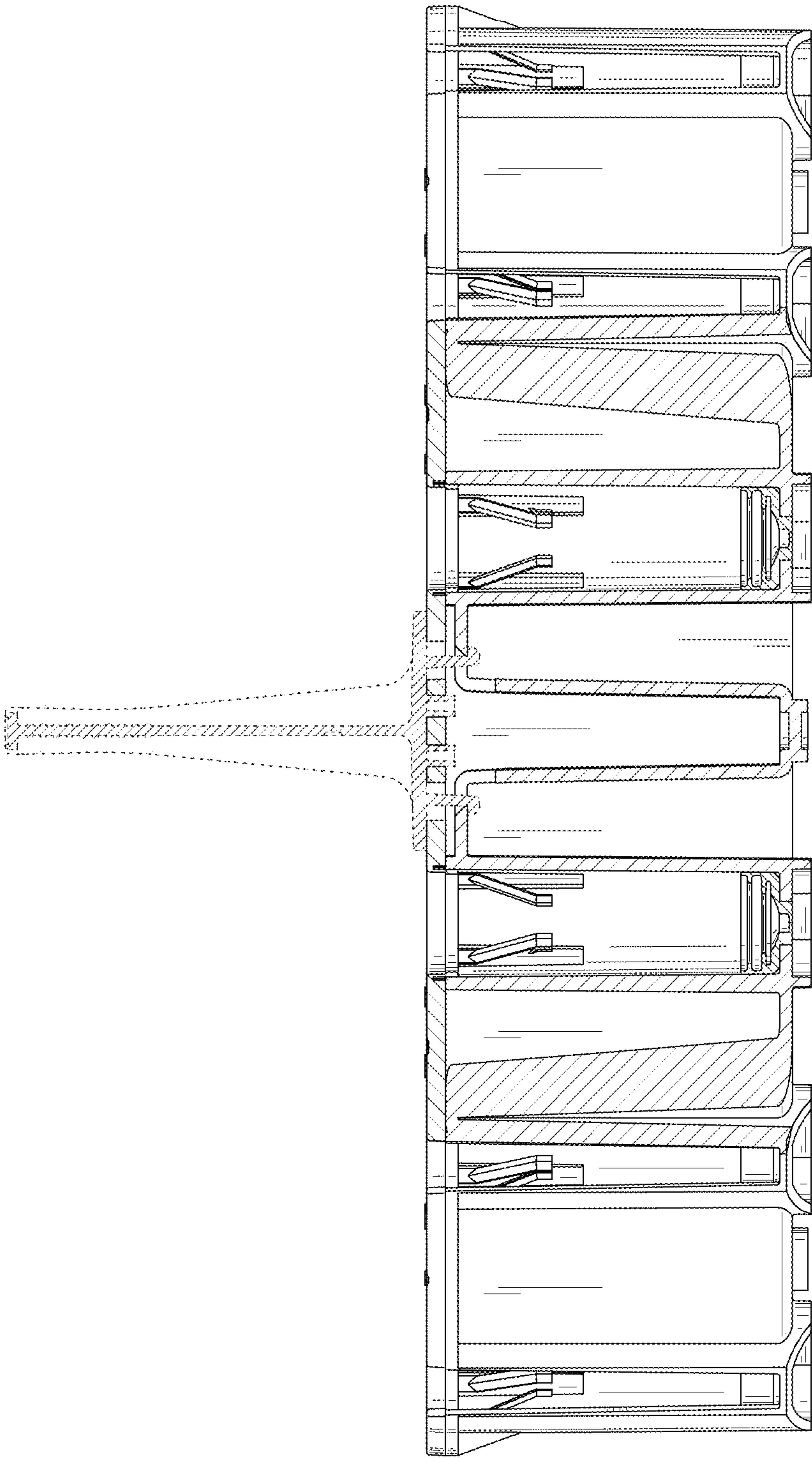


FIG. 12

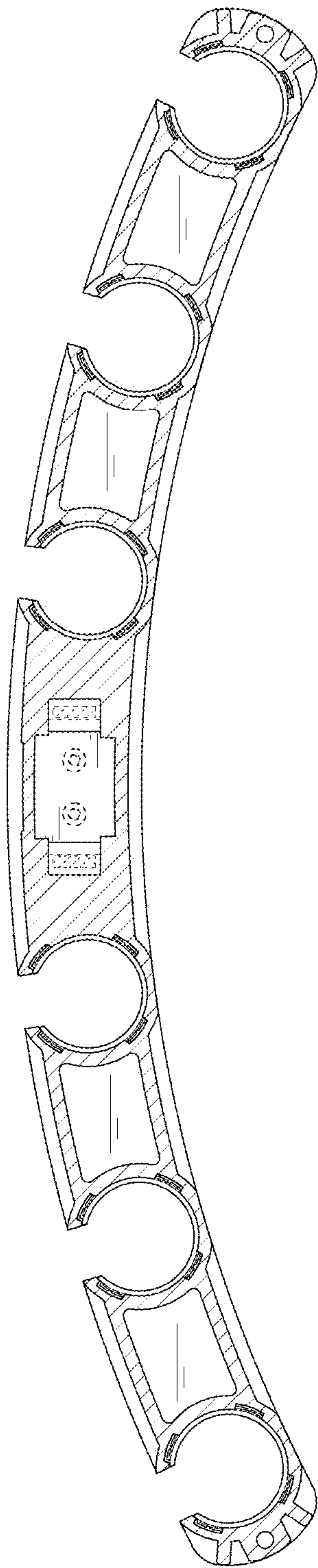


FIG. 13

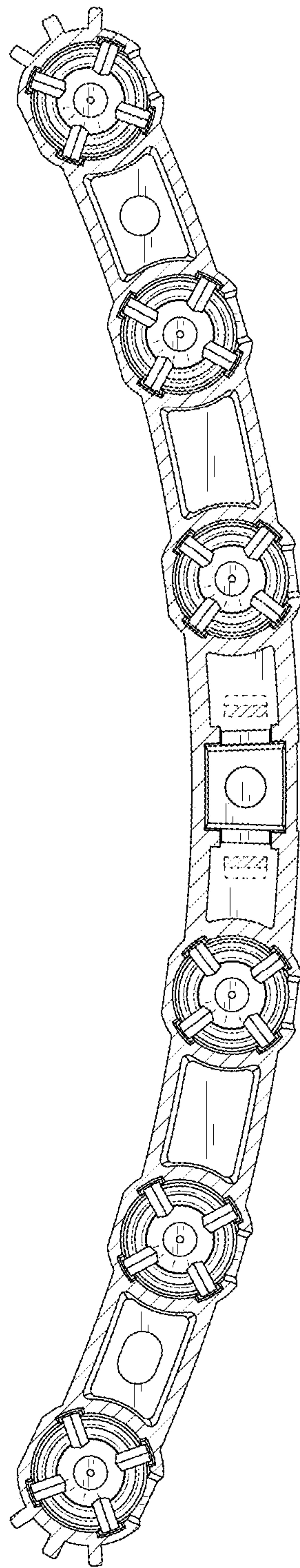


FIG. 14